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said projected beams are configured to project said markers onto said field of view to provide information for the analysis of an image of said field of view and said markers captured at said image plate in order to establish a set of orientation values describing the orientation of the image plate, at image capture, to selected regions of reflectivity in said field of view, said selected regions of reflectivity not being comprised by said reference plane.

35. An apparatus as claimed in claim 34, wherein said markers form a predefined pattern in said field of view. 10

36. An apparatus as claimed in claim 34, wherein said electromagnetic radiation comprises radiation of a wavelength in the range 10^{-15} m to 10^{-6} m.

37. An apparatus as claimed in claim 34, wherein said image plate comprises a CCD or CMOS array. 15

38. An apparatus as claimed in claim 34, wherein said image plate is comprised by a digital camera, said means to locate said image plate configured to engage said digital

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camera for the location of said digital camera in fixed spatial and angular orientation on said projection unit.

39. An apparatus as claimed in claim 34, wherein said electromagnetic radiation comprises visible light of a wavelength in the range 400 nm to 700 nm. 5

40. An apparatus as claimed in claim 34, wherein said projection unit further comprises a body portion, said body portion defining a fixed location of said origins and a fixed location of said means to locate said image plate.

41. An apparatus as claimed in claim 34, wherein said orientation values enable the reconstruction of a positional data set describing the real world position of said selected regions of reflectivity in said field of view in one, two or three-dimensions.

42. An apparatus as claimed in claim 34, wherein said projection unit further comprises means to focus said beams.

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